

100V N-Channel Split Gate MOSFET

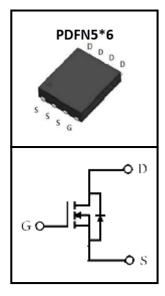
FEATURES

- Super Low Gate Charge
- 100% EAS Guaranteed
- RoHS compliant
- Green Device Available
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

APPLICATIONS

- DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification





Device Marking and Package Information				
Device	Package	Marking		
CSN10N9P5B	PDFN5*6	CSN10N9P5B		

Absolute Maximum Ratings at T _j = 25°C unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	100	V
Continuous Drain Current T _C = 25°C	(note1)	,	60	Α
Continuous Drain Current T _C = 100°C	(note1)	I _D	38	Α
Pulsed Drain Current	(note2)	I _{DM}	240	А
Gate Source Voltage		V _{GSS}	±20	V
Single Pulse Avalanche Energy	(note3)	E _{AS}	14	mJ
Power Dissipation T _C = 25°C	(note4)	P _D	63	W
Operating Junction and Storage Temperatu	ıre Range	T _J , T _{stg}	-55~+150	∘C

Thermal Characteristics					
Parameter		Symbol	Value	Unit	
Thermal Resistance, Junction-to-Case	(note1)	$R_{ heta JC}$	2.0	°C/W	
Thermal Resistance, Junction-to-Ambient	(note1)	$R_{\theta JA}$	55	°C/W	



Electrical Characteristics T _j		Value				
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = 250\mu A$	100			V
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	uA
		$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 55^{\circ}C$			5	uA
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 20V$			±100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2	2	2.6	V
	-	$V_{GS} = 10V, I_{D} = 20A$		8.2	9.5	mΩ
Drain-Source On-Resistance (note2)	$R_{DS(on)}$	$V_{GS} = 4.5V, I_{D} = 10A$		11.3	14	mΩ
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0V$,		2122		pF
Output Capacitance	C _{oss}	$V_{DS} = 50V$,		618		
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		25		
Gate Resistance	R_g	V _{GS} = 0V,f = 1.0MHz		1.94		Ω
Total Gate Charge	Q_g			41.8		nC
Gate-Source Charge	Q_{gs}	$V_{DD} = 50V, I_{D} = 20A,$ $V_{GS} = 10V$		9		
Gate-Drain Charge	Q_{gd}	V GS = 10 V		10		
Turn-on Delay Time	t _{d(on)}			17		
Turn-on Rise Time	t _r	$V_{DS} = 50V, I_{D} = 20A$		4		ns
Turn-off Delay Time	t _{d(off)}	$V_{GS} = 10V, R_G = 3\Omega$		32		
Turn-off Fall Time	t _f			8		
Body Diode Characteristics						
Source-Drain Current(Body Diode)	I _{SD}				60	А
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}, I_{SD} = 20\text{A}, V_{GS} = 0\text{V}$		0.88	1.0	V
Reverse Recovery Time	t _{rr}	$T_{J} = 25^{\circ}C, I_{F} = 20A$		50.5		ns
Reverse Recovery Charge	Q _{rr}	$di_F/dt = 100A/\mu s$		71.5		nC

Notes

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width $\leq\!\!300 us$, duty cycle $\!\!\leq\!\!2\%$
- 3. The EAS data shows Max. rating . The test condition is VDD =50V,VGS =10V,L=0.5mH
- 4. The power dissipation is limited by 175°C junction temperature
- 5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics T₁ = 25°C, unless otherwise noted

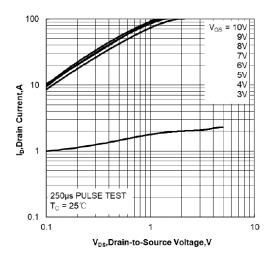


Figure 1. Output Characteristics

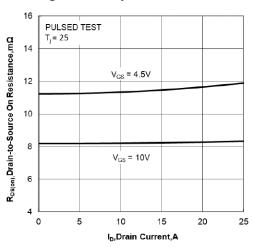


Figure 3. Drain-to-Source On Resistance vs Drain Current

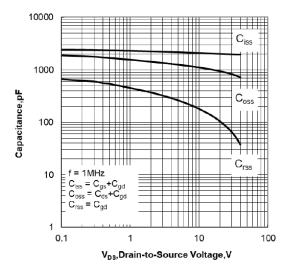


Figure 5. Capacitance Characteristics

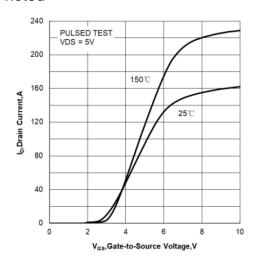


Figure 2. Transfer Characteristics

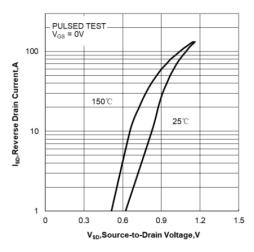


Figure 4. Body Diode Forward Voltage vs Source Current and Temperature

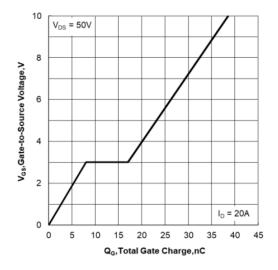


Figure 6. Gate Charge Characteristics



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

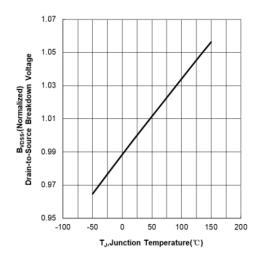


Figure 7. Normalized Breakdown Voltage vs Junction Temperature

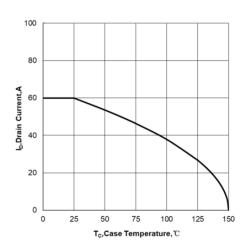


Figure 9. Maximum Continuous Drain Current vs Case Temperature

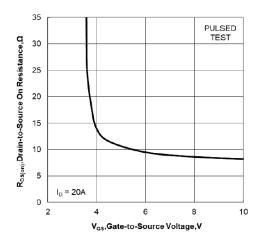


Figure11. Drain-to-Source On Resistance vs Gate
Voltage and Drain Current

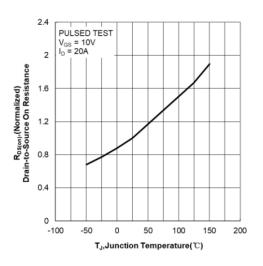


Figure 8. Normalized On Resistance vs

Junction Temperature

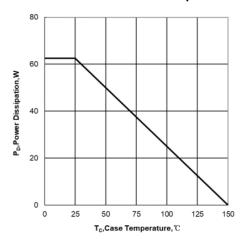


Figure 10. Maximum Power Dissipation vs Case Temperature

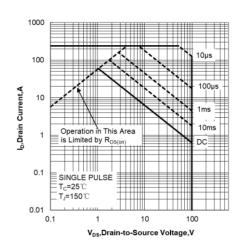


Figure 12. Maximum Safe Operating Area



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

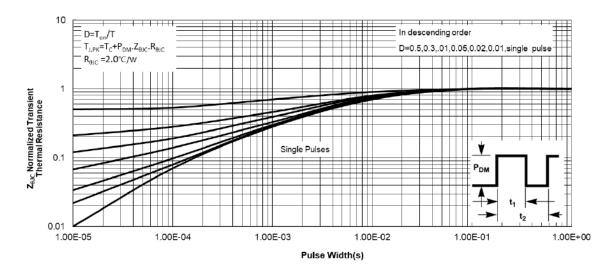


Figure 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Figure A: Gate Charge Test Circuit and Waveform

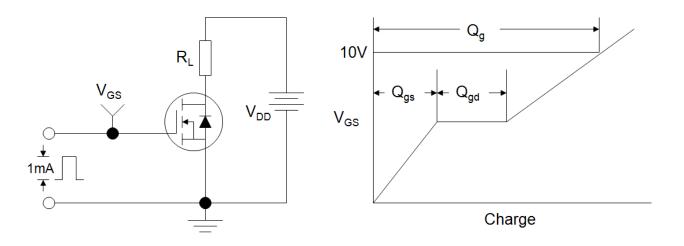


Figure B: Resistive Switching Test Circuit and Waveform

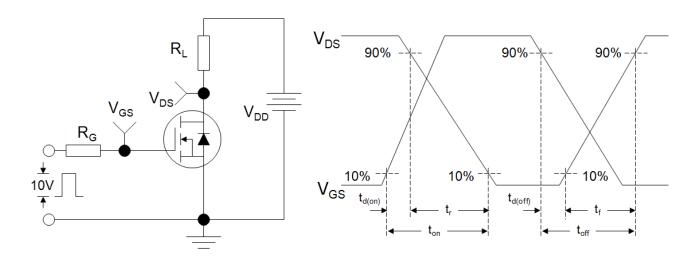
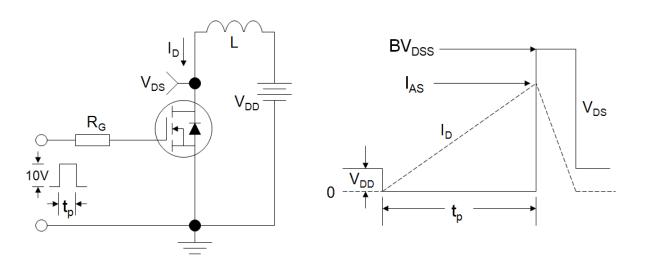
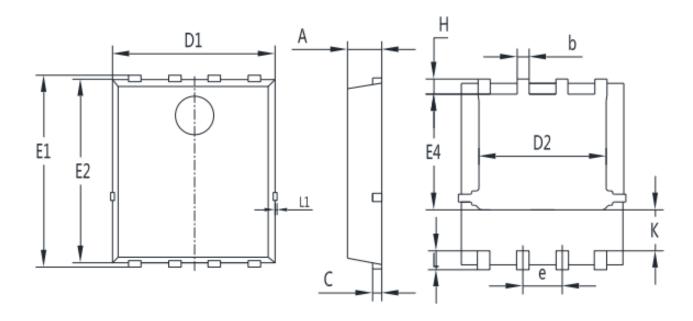


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





PDFN5*6



SYMBOLS	MILLIMETERS			
STIVIBULS	MIN	MAX		
Α	1.00	1.20		
b	0.30	0.50		
С	0.15	0.35		
D1	5.00	5.40		
D2	3.80	4.25		
е	1.17	1.37		
E1	5.95	6.35		
E2	5.66	6.06		
E4	3.52	3.92		
Н	0.40	0.60		
L	0.30	0.70		
L1	0.12REF			
K	1.15	1.45		



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